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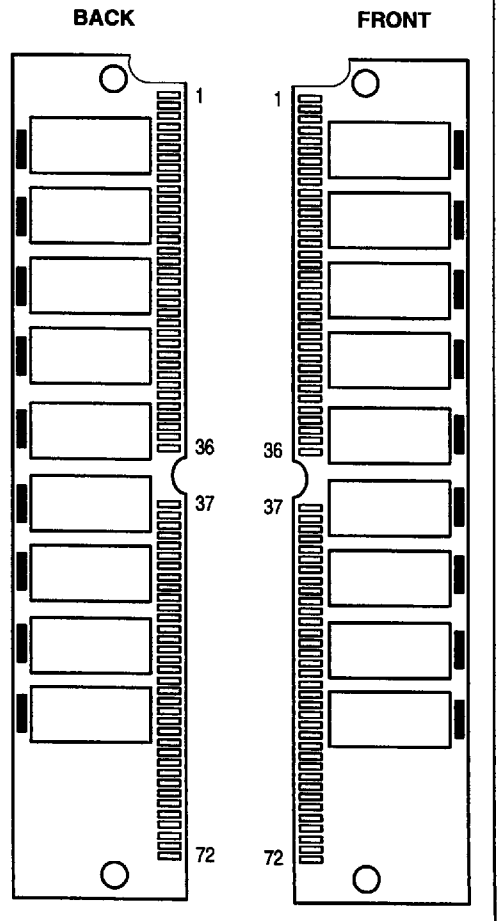
4, 8M x 36
5 V, FPM, Unbuffered

DRAM Single-In-Line Memory Module (SIMM)
Error Correction Pinout for Parity Applications
16 and 32 Megabyte

- JEDEC–Standard 72–Lead Single–In–Line Memory Module (SIMM)
- Single 5 V Power Supply, TTL–Compatible Inputs and Outputs
- Fast Page Mode (FPM)
- $\overline{RAS}$–Only Refresh, $\overline{CAS}$ Before $\overline{RAS}$ Refresh, Hidden Refresh
- 2048 Cycle Refresh: 32 ms (Max)
- Early–Write Common I/O Capability
- Unlatched Data Out at Cycle End Allows Two Dimensional Chip Selection

4M x 36 (16MB), 8M x 36 (32MB)
72–LEAD SIMM
CASE 866–02



* BACK NOT POPULATED ON 4M x 36 (16MB)

PART NUMBERS (See Last Page of Data Sheet for Definitions)

Organization	60	70
4M x 36	MCM36C404ASH60 MCM36C404ASHG60	MCM36C404ASH70 MCM36C404ASHG70
8M x 36	MCM36C804ASH60 MCM36C804ASHG60	MCM36C804ASH70 MCM36C804ASHG70

KEY TIMING PARAMETERS

Speed	t_{RC} (ns)	t_{RAC} (ns)	t_{CAC} (ns)	t_{AA} (ns)	t_{PC} (ns)
60	110	60	15	30	40
70	130	70	20	35	45

ADDITIONAL PARAMETERS

Configuration	Speed	Active Power Dissipation (mW) (Max)	Standby Power Dissipation (mW) (Max)	
			TTL	CMOS
16MB	60	5,445	99	50
	70	4,703		
32MB	60	5,544	198	99
	70	4,802		

4/7/97

PIN ASSIGNMENTS

Pin	Name	Pin	Name	Pin	Name	Pin	Name	Pin	Name	Pin	Name
1	V_{SS}	13	A1	25	DQ13	37	DQ19	49	DQ22	61	DQ33
2	DQ0	14	A2	26	DQ14	38	DQ20	50	DQ23	62	DQ34
3	DQ1	15	A3	27	DQ15	39	V_{SS}	51	DQ24	63	DQ35
4	DQ2	16	A4	28	A7	40	$\overline{CAS0}$	52	DQ25	64	NC
5	DQ3	17	A5	29	DQ16	41	A10	53	DQ26	65	NC
6	DQ4	18	A6	30	V_{CC}	42	NC	54	DQ27	66	NC
7	DQ5	19	$\overline{G}$	31	A8	43	$\overline{CAS1}$*	55	DQ28	67	PD1
8	DQ6	20	DQ8	32	A9	44	$\overline{RAS0}$	56	DQ29	68	PD2
9	DQ7	21	DQ9	33	NC	45	$\overline{RAS1}$*	57	DQ30	69	PD3
10	V_{CC}	22	DQ10	34	NC	46	DQ21	58	DQ31	70	PD4
11	PD5	23	DQ11	35	DQ17	47	$\overline{W}$	59	V_{CC}	71	NC
12	A0	24	DQ12	36	DQ18	48	$\overline{ECC}$	60	DQ32	72	V_{SS}

* NC on 16MB.

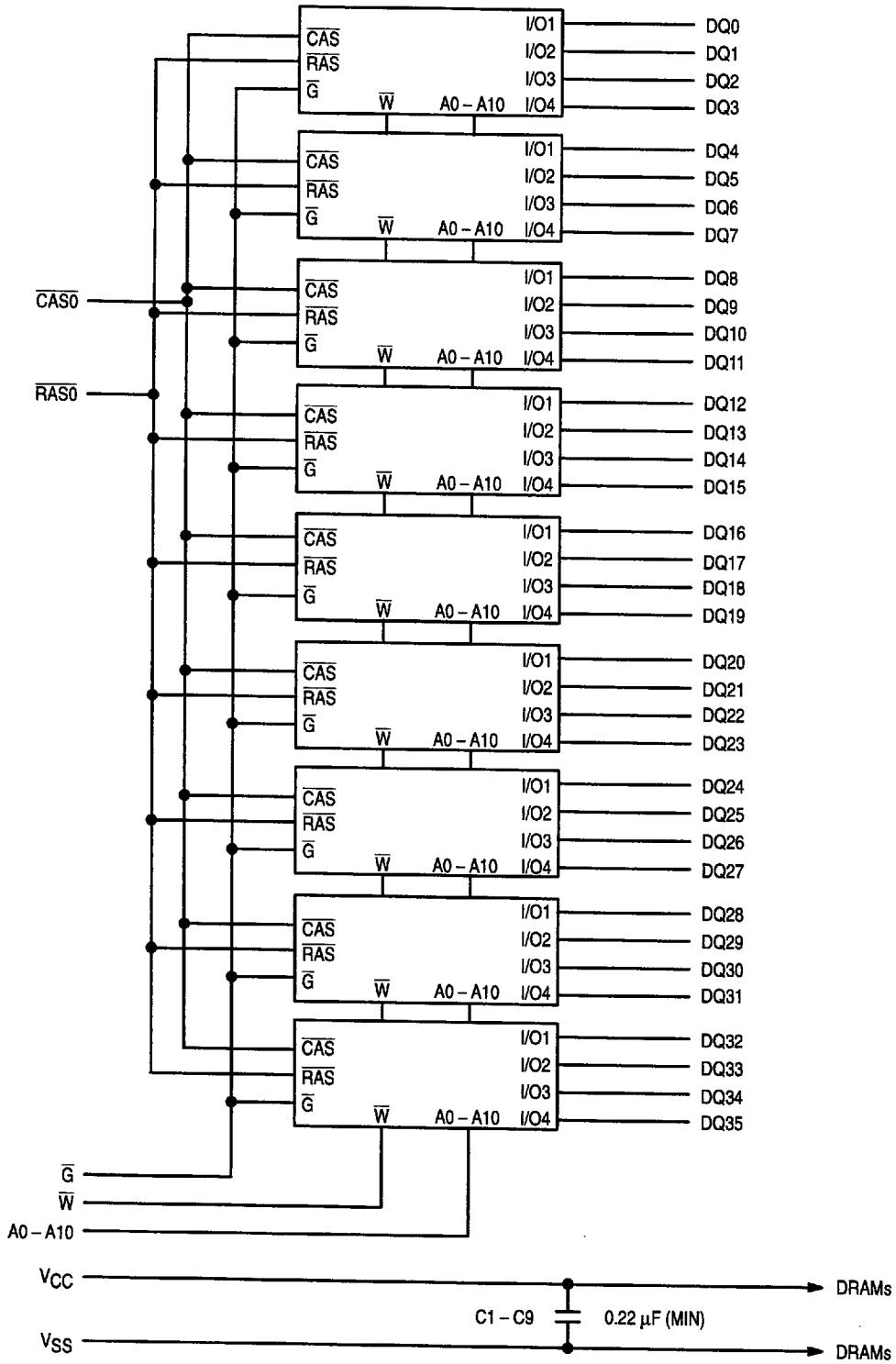
PIN NAMES	
A0 – A10	Address Inputs
DQ0 – DQ35	Data Input/Output
$\overline{CAS0}$ – $\overline{CAS1}$	Column Address Strobe
PD1 – PD5	Presence Detect
$\overline{RAS0}$ – $\overline{RAS1}$	Row Address Strobe
$\overline{W}$	Read/Write Input
$\overline{ECC}$	Configuration Detection
$\overline{G}$	Output Enable
V_{CC}	Power
V_{SS}	Ground
NC	No Connection

PRESENCE DETECT

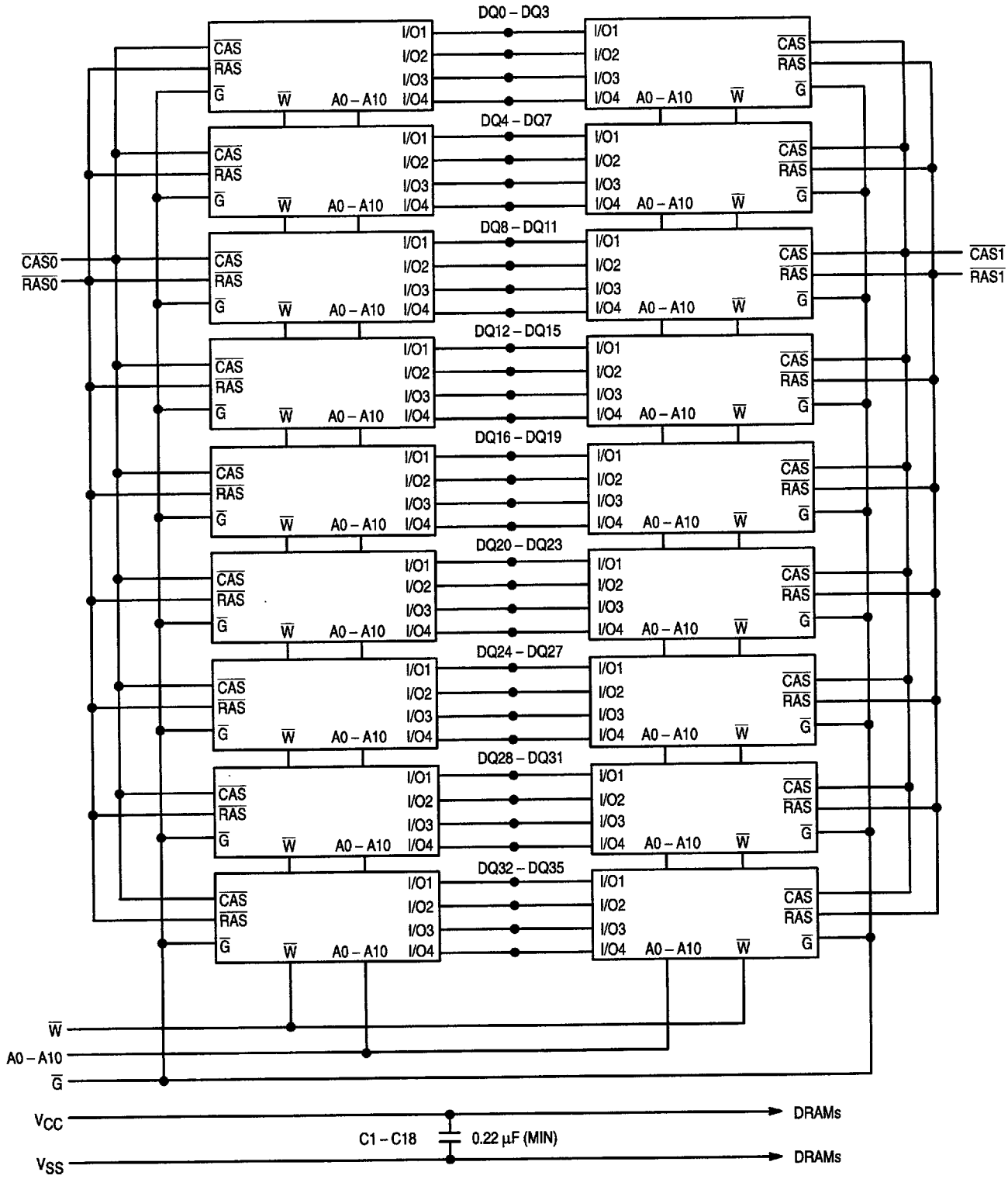
Pin Names	Speed	16MB	32MB
PD1		V_{SS}	NC
PD2		NC	V_{SS}
PD3	60	NC	NC
	70	V_{SS}	V_{SS}
PD4	60	NC	NC
	70	NC	NC
PD5*		V_{SS}	V_{SS}
E_{CC}		V_{SS}	V_{SS}

* PD5 tied to V_{SS} through a 2.6 kΩ resistor.

16MB BLOCK DIAGRAM



32MB BLOCK DIAGRAM



ABSOLUTE MAXIMUM RATINGS (See Note)

Rating		Symbol	Value	Unit
Power Supply Voltage		V_{CC}	– 0.5 to + 7	V
Voltage Relative to V_{SS} for Any Pin Except V_{CC}		V_{in}, V_{out}	– 0.5 to + 7	V
Data Output Current		I_{out}	50	mA
Power Dissipation	16MB 32MB	P_D	8.1 16.2	W
Operating Temperature Range		T_A	0 to + 70	°C
Storage Temperature Range		T_{stg}	– 55 to + 125	°C

NOTE: Permanent device damage may occur if ABSOLUTE MAXIMUM RATINGS are exceeded. Functional operation should be restricted to RECOMMENDED OPERATING CONDITIONS. Exposure to higher than recommended voltages for extended periods of time could affect device reliability.

This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields; however, it is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltages to these high–impedance circuits.

DC OPERATING CONDITIONS AND CHARACTERISTICS

(V_{CC} = 5.0 V ± 10%, T_A = 0 to 70°C, Unless Otherwise Noted)

RECOMMENDED OPERATING CONDITIONS (All voltages referenced to V_{SS})

Parameter	Symbol	Min	Typ	Max	Unit
Supply Voltage (Operating Voltage Range)	V_{CC}	4.5	5.0	5.5	V
	V_{SS}	0	0	0	
Logic High Voltage, All Inputs	V_{IH}	2.4	—	V_{CC} + 0.5 V	V
Logic Low Voltage, All Inputs	V_{IL}	– 0.5*	—	0.8	V
Input Leakage Current (0 V ≤ V_{in} ≤ V_{CC})	$I_{lkg(I)}$	– 180	—	180	µA
Output Leakage Current (0 V ≤ V_{out} ≤ V_{CC}, Output Disable)	$I_{lkg(O)}$	– 20	—	20	µA
Output High Voltage (I_{OH} = – 5 mA)	V_{OH}	2.4	—	—	V
Output Low Voltage (I_{OL} = 4.2 mA)	V_{OL}	—	—	0.4	V

* – 2.0 V at pulse width ≤ 20 ns.

DC CHARACTERISTICS AND SUPPLY CURRENTS (All voltages referenced to V_{SS})

Characteristic		Symbol	16MB		32MB		Unit	Notes
			Min	Max	Min	Max		
V_{CC} Power Supply Current (t_{RC} = t_{RC} Min)	60 70	I_{CC1}	— —	990 855	— —	1008 873	mA	1, 2
V_{CC} Power Supply Current (Standby) ($\overline{RAS}$ = $\overline{CAS}$ = V_{IH})		I_{CC2}	—	18	—	36	mA	1, 2, 3
V_{CC} Power Supply Current During $\overline{RAS}$–Only Refresh Cycles ($\overline{CAS}$ = V_{IH}) (t_{RC} = t_{RC} Min)	60 70	I_{CC3}	— —	990 855	— —	1008 873	mA	
V_{CC} Power Supply Current During EDO Cycle ($\overline{RAS}$ = V_{IL}) (t_{PC} = t_{PC} Min)	60 70	I_{CC4}	— —	630 540	— —	648 558	mA	1, 2
V_{CC} Power Supply Current (Standby) ($\overline{RAS}$ = $\overline{CAS}$ = V_{CC} – 0.2 V)		I_{CC5}	—	9	—	18	mA	
V_{CC} Power Supply Current During $\overline{CAS}$ Before $\overline{RAS}$ Refresh Cycle (t_{RC} = t_{RC} Min)	60 70	I_{CC6}	— —	990 855	— —	1008 873	mA	1

NOTES:
1. Current is a function of cycle rate and output loading; maximum currents are specified cycle time (minimum) with the output open.
2. Address may be changed once or less while $\overline{RAS}$ = V_{IL}. In the case of I_{CC4}, it can be changed once or less during t_{PC}.
3. Assumes both banks not refreshed simultaneously on 32MB.

CAPACITANCE (f = 1.0 MHz, T_A = 25°C, V_{CC} = 5 V, Periodically Sampled Rather Than 100% Tested)

Input Capacitance	Symbol	16MB Max	32MB Max	Unit
Addresses	C_{in}	55	100	pF
$\overline{WE}$, $\overline{G}$	C_{in}	73	136	pF
$\overline{RAS}$	C_{in}	73	73	pF
$\overline{CAS}$	C_{in}	73	73	pF
DQ	C_{out}	17	24	pF

NOTE: Capacitance measured with a Boonton Meter or effective capacitance calculated from the equation: $C = I\ \Delta t/\Delta V$.

AC OPERATING CONDITIONS AND CHARACTERISTICS

(V_{CC} = 5.0 V ± 10%, T_A = 0 to 70°C, Unless Otherwise Noted)

READ, WRITE, AND READ–WRITE CYCLES (See Notes 1, 2, 3, and 4)

Parameter	Symbol		60		70		Unit	Notes
	Std	Alt	Min	Max	Min	Max		
Random Read or Write Cycle Time	t_{RELREL}	t_{RC}	110	—	130	—	ns	5
Read–Write Cycle Time	t_{RELREL}	t_{RWC}	155	—	180	—	ns	5
Access Time from $\overline{RAS}$	t_{RELQV}	t_{RAC}	—	60	—	70	ns	6, 7
Access Time from $\overline{CAS}$	t_{CELQV}	t_{CAC}	—	15	—	20	ns	6, 8
Access Time from Column Address	t_{AVQV}	t_{AA}	—	30	—	35	ns	6, 9
Access Time from Precharge $\overline{CAS}$	t_{CEHQV}	t_{CPA}	—	35	—	40	ns	6
$\overline{CAS}$ to Output in Low–Z	t_{CELQX}	t_{CLZ}	0	—	0	—	ns	6
Output Buffer and Turn–Off Delay	t_{CEHQZ}	t_{OFF}	0	15	0	15	ns	10
Transition Time (Rise and Fall)	t_T	t_T	3	50	3	50	ns	
$\overline{RAS}$ Precharge Time	t_{REHREL}	t_{RP}	40	—	50	—	ns	
$\overline{RAS}$ Pulse Width	t_{RELREH}	t_{RAS}	60	10 k	70	10 k	ns	
$\overline{RAS}$ Hold Time	t_{CELREH}	t_{RSH}	15	—	20	—	ns	
$\overline{CAS}$ Hold Time	t_{RELCEH}	t_{CSH}	60	—	70	—	ns	
$\overline{CAS}$ Precharge to $\overline{RAS}$ Hold Time	t_{CEHREH}	t_{RHCP}	35	—	40	—	ns	
$\overline{CAS}$ Pulse Width	t_{CELCEH}	t_{CAS}	15	10 k	20	10 k	ns	
$\overline{RAS}$ to $\overline{CAS}$ Delay Time	t_{RELCEL}	t_{RCD}	20	45	20	50	ns	11
$\overline{RAS}$ to Column Address Delay Time	t_{RELAV}	t_{RAD}	15	30	15	35	ns	12
$\overline{CAS}$ to $\overline{RAS}$ Precharge Time	t_{CEHREL}	t_{CRP}	5	—	5	—	ns	

NOTES: (continued)

1. V_{IH} (min) and V_{IL} (max) are reference levels for measuring timing of input signals. Transition times are measured between V_{IH} and V_{IL}.
2. An initial pause of 200 µs is required after power–up followed by 8 $\overline{RAS}$ cycles before proper device operation is guaranteed.
3. The transition time specification applies for all input signals. In addition to meeting the transition rate specification, all input signals must transition between V_{IH} and V_{IL} (or between V_{IL} and V_{IH}) in a monotonic manner.
4. AC measurements t_T = 5.0 ns.
5. The specification for t_{RC} (min) is used only to indicate cycle time at which proper operation over the full temperature range (0°C ≤ T_A ≤ 70°C) is ensured.
6. Measured with a current load equivalent to 2 TTL (– 200 µA, + 4 mA) loads and 100 pF with the data output trip points set at V_{OH} = 2.0 V and V_{OL} = 0.8 V.
7. Assumes that $t_{RCD} \leq t_{RCD}$ (max).
8. Assumes that $t_{RCD} \geq t_{RCD}$ (max).
9. Assumes that $t_{RAD} \geq t_{RAD}$ (max).
10. t_{OFF} (max) defines the time at which the output achieves the open circuit condition and is not referenced to output voltage levels.
11. Operation within the t_{RCD} (max) limit ensures that t_{RAC} (max) can be met. t_{RCD} (max) is specified as a reference point only; if t_{RCD} is greater than the specified t_{RCD} (max) limit, then access time is controlled exclusively by t_{CAC}.
12. Operation within the t_{RAD} (max) limit ensures that t_{RAC} (max) can be met. t_{RAD} (max) is specified as a reference point only; if t_{RAD} is greater than the specified t_{RAD} (max), then access time is controlled exclusively by t_{AA}.

READ, WRITE, AND READ–WRITE CYCLES (Continued)

Parameter	Symbol		60		70		Unit	Notes
	Std	Alt	Min	Max	Min	Max		
$\overline{CAS}$ Precharge Time	t_{CEHCEL}	t_{CP}	10	—	10	—	ns	
Row Address Setup Time	t_{AVREL}	t_{ASR}	0	—	0	—	ns	
Row Address Hold Time	t_{RELAX}	t_{RAH}	10	—	10	—	ns	
Column Address Setup Time	t_{AVCEL}	t_{ASC}	0	—	0	—	ns	
Column Address Hold Time	t_{CELAX}	t_{CAH}	10	—	15	—	ns	
Column Address to $\overline{RAS}$ Lead Time	t_{AVREH}	t_{RAL}	30	—	35	—	ns	
Read Command Setup Time	t_{WHCEL}	t_{RCS}	0	—	0	—	ns	
Read Command Hold Time Referenced to $\overline{CAS}$	t_{CEHWX}	t_{RCH}	0	—	0	—	ns	13
Read Command Hold Time Referenced to $\overline{RAS}$	t_{REHWX}	t_{RRH}	0	—	0	—	ns	13
Write Command Hold Time Referenced to $\overline{CAS}$	t_{CELWH}	t_{WCH}	10	—	15	—	ns	
Write Command Pulse Width	t_{WLWH}	t_{WP}	10	—	15	—	ns	
Write Command to $\overline{RAS}$ Lead Time	t_{WLREH}	t_{RWL}	15	—	20	—	ns	
Write Command to $\overline{CAS}$ Lead Time	t_{WLCEH}	t_{CWL}	15	—	20	—	ns	
Data In Setup Time	t_{DVCEL}	t_{DS}	0	—	0	—	ns	14
Data In Hold Time	t_{CELDX}	t_{DH}	10	—	15	—	ns	14
Write Command Setup Time	t_{WLCEL}	t_{WCS}	0	—	0	—	ns	15
$\overline{CAS}$ to Write Delay	t_{CELWL}	t_{CWD}	40	—	45	—	ns	15
$\overline{RAS}$ to Write Delay	t_{RELWL}	t_{RWD}	85	—	95	—	ns	15
Column Address to Write Delay	t_{AVWL}	t_{AWD}	55	—	60	—	ns	15
Refresh Period	t_{RVRV}	t_{RFSH}	—	32	—	32	ms	
$\overline{CAS}$ Setup Time for $\overline{CAS}$ Before $\overline{RAS}$ Refresh	t_{RELCEL}	t_{CSR}	5	—	5	—	ns	
$\overline{CAS}$ Hold Time for $\overline{CAS}$ Before $\overline{RAS}$ Refresh	t_{RELCEH}	t_{CHR}	10	—	15	—	ns	
$\overline{RAS}$ Precharge to $\overline{CAS}$ Active Time	t_{REHCEL}	t_{RPC}	5	—	5	—	ns	
$\overline{CAS}$ Precharge Time for $\overline{CAS}$ Before $\overline{RAS}$ Counter Time	t_{CEHCEL}	t_{CPT}	20	—	20	—	ns	
Write Command Setup Time (Test Mode)	t_{WLREL}	t_{WTS}	10	—	10	—	ns	
Write Command Hold Time (Test Mode)	t_{RELWH}	t_{WTH}	10	—	10	—	ns	
Write to $\overline{RAS}$ Precharge Time ($\overline{CAS}$ Before $\overline{RAS}$ Refresh)	t_{WHREL}	t_{WRP}	10	—	10	—	ns	
Write to $\overline{RAS}$ Hold Time ($\overline{CAS}$ Before $\overline{RAS}$ Refresh)	t_{RELWL}	t_{WRH}	10	—	10	—	ns	
$\overline{RAS}$ Hold Time Referenced to $\overline{G}$	t_{GLREH}	t_{ROH}	10	—	10	—	ns	
$\overline{G}$ Access Time	t_{GLQV}	t_{GA}	—	15	—	15	ns	6
$\overline{G}$ to Data Delay	t_{GLHDX}	t_{GD}	15	—	15	—	ns	
Output Buffer Turn–Off Delay Time from $\overline{G}$	t_{GHQZ}	t_{GZ}	0	15	0	15	ns	17
$\overline{G}$ Command Hold Time	t_{WLGL}	t_{GH}	10	—	15	—	ns	
Output Disable Setup Time	t_{GHCEL}	t_{ODS}	0	—	0	—	ns	

NOTES:

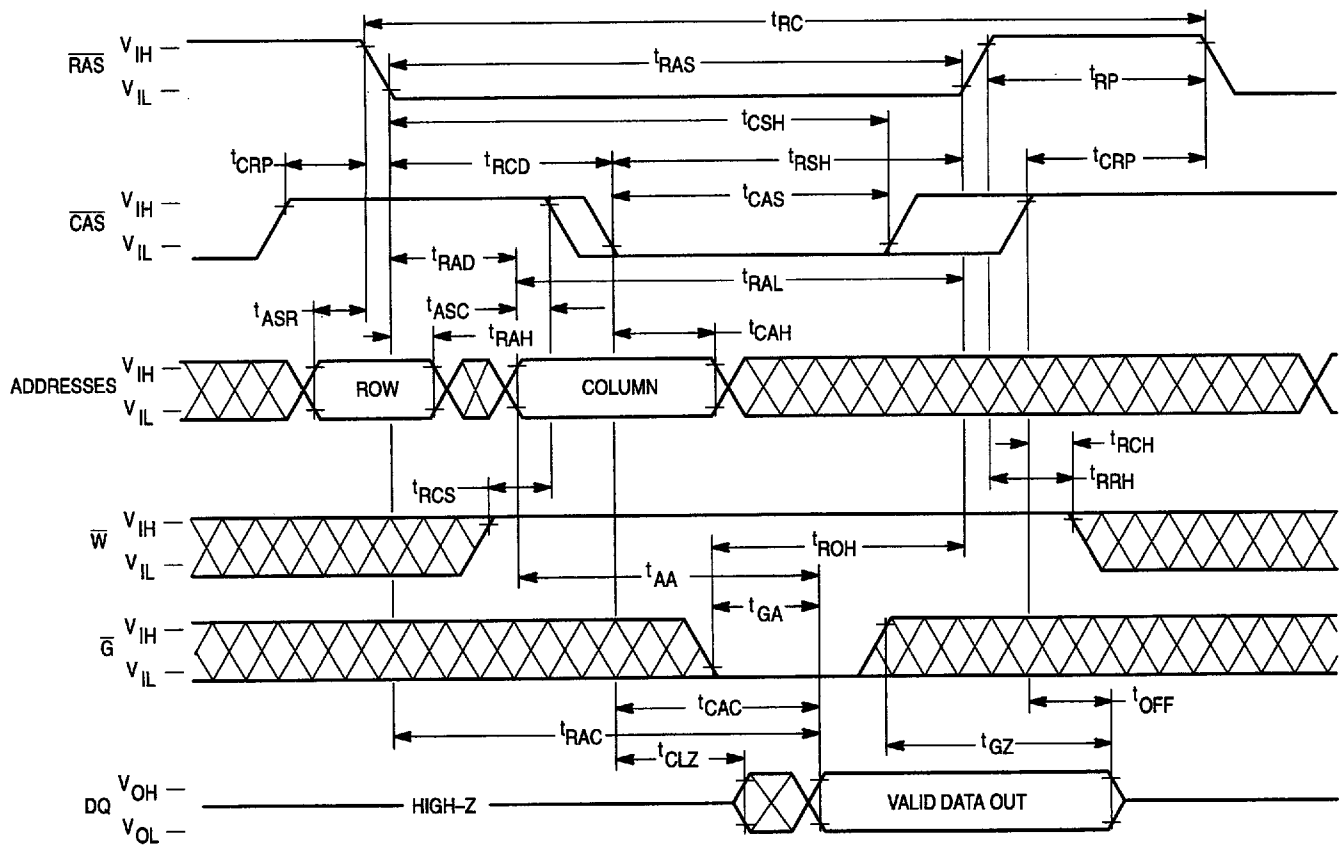
13. Either t_{RRH} or t_{RCH} must be satisfied for a read cycle.
14. These parameters are referenced to $\overline{CAS}$ leading edge in early write cycles and to $\overline{W}$ leading edge in late write or read–write cycles.
15. t_{WCS}, t_{RWD}, t_{CWD}, t_{AWD}, and t_{CPWD} are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only; if $t_{WCS} \geq t_{WCS}$ (min), the cycle is an early write cycle and the data out pin will remain open circuit (high impedance) throughout the entire cycle; if $t_{CWD} \geq t_{CWD}$ (min), $t_{RWD} \geq t_{RWD}$ (min), $t_{AWD} \geq t_{AWD}$ (min), and $t_{CPWD} \geq t_{CPWD}$ (min) (page mode), the cycle is a read–write cycle and the data out will contain data read from the selected cell. If neither of these sets of conditions is satisfied, the condition of the data out (at access time) is indeterminate.
16. To avoid bus contention and potential damage to the module, $\overline{RAS0}$ and $\overline{RAS1}$ may not be active low simultaneously.
17. t_{OFF} (max) and/or t_{GZ} (max) define the time at which the output achieves the open circuit condition and is not referenced to output voltage levels.

FAST PAGE MODE READ, WRITE, AND READ–WRITE CYCLES (See Notes 1, 2, 3, and 4)

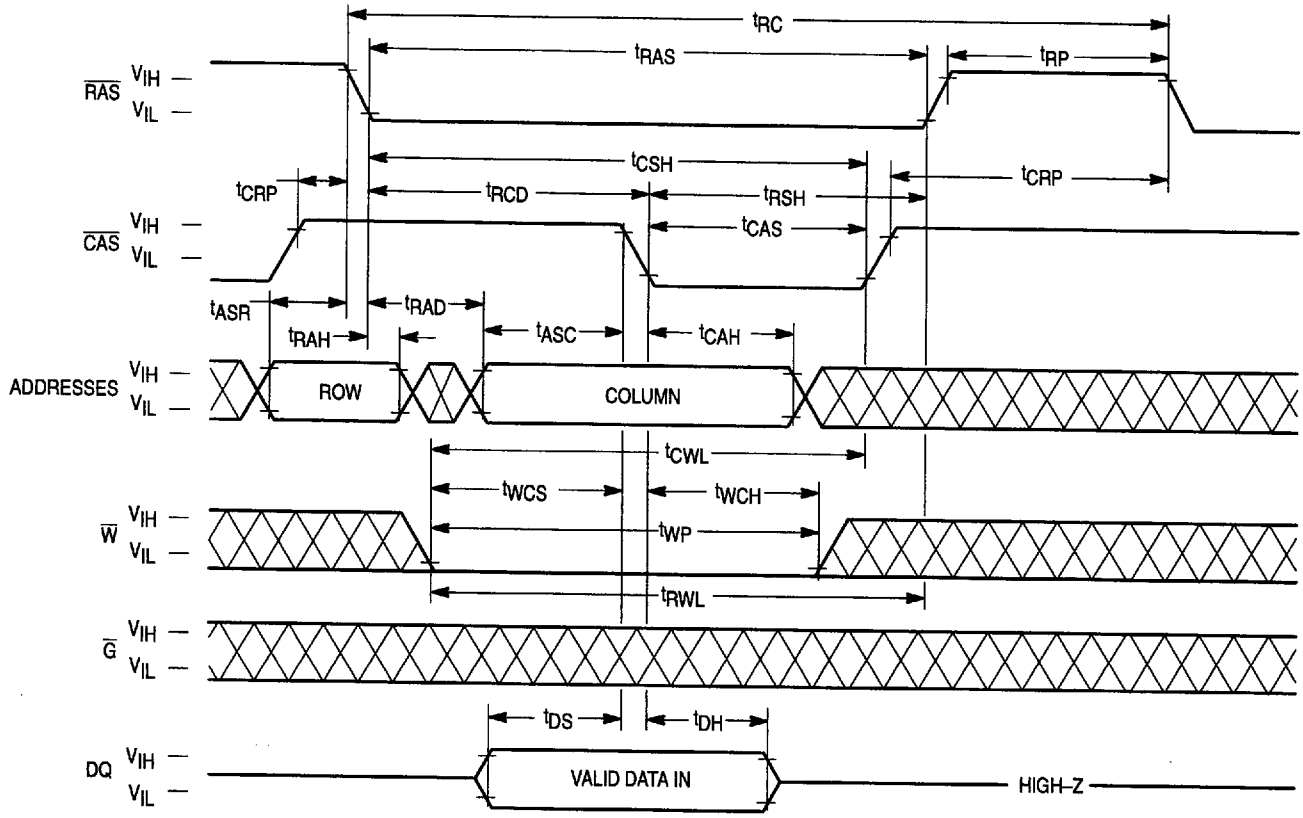
Parameter	Symbol		60		70		Unit	Notes
	Std	Alt	Min	Max	Min	Max		
Fast Page Mode Cycle Time	t_{CELCEL}	t_{PC}	40	—	45	—	ns	
$\overline{CAS}$ Precharge to $\overline{RAS}$ Hold Time (Fast Page Mode)	t_{CEHREH}	t_{RHCP}	35	—	40	—	ns	
Fast Page Mode Read–Write Cycle Time	t_{CELCEL}	t_{PRWC}	85	—	90	—	ns	
$\overline{RAS}$ Pulse Width (Fast Page Mode)	t_{RELREH}	t_{RASP}	60	200 k	70	200 k	ns	
$\overline{CAS}$ Precharge to Write Delay	t_{CEHWL}	t_{CPWD}	60	—	65	—	ns	5

NOTES:
1. V_{IH} (min) and V_{IL} (max) are reference levels for measuring timing of input signals. Transition times are measured between V_{IH} and V_{IL}.
2. An initial pause of 200 µs is required after power–up followed by 8 $\overline{RAS}$ cycles before proper device operation is guaranteed.
3. The transition time specification applies for all input signals. In addition to meeting the transition rate specification, all input signals must transition between V_{IH} and V_{IL} (or between V_{IL} and V_{IH}) in a monotonic manner.
4. AC measurements t_T = 5.0 ns.
5. t_{WCS}, t_{RWD}, t_{CWD}, t_{AWD}, and t_{CPWD} are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only; if $t_{WCS} \geq t_{WCS}$ (min), the cycle is an early write cycle and the data out pin will remain open circuit (high impedance) through–out the entire cycle; if $t_{CWD} \geq t_{CWD}$ (min), $t_{RWD} \geq t_{RWD}$ (min), $t_{AWD} \geq t_{AWD}$ (min), and $t_{CPWD} \geq t_{CPWD}$ (min) (page mode), the cycle is a read–write cycle and the data out will contain data read from the selected cell. If neither of these sets of conditions is satisfied, the condition of the data out (at access time) is indeterminate.

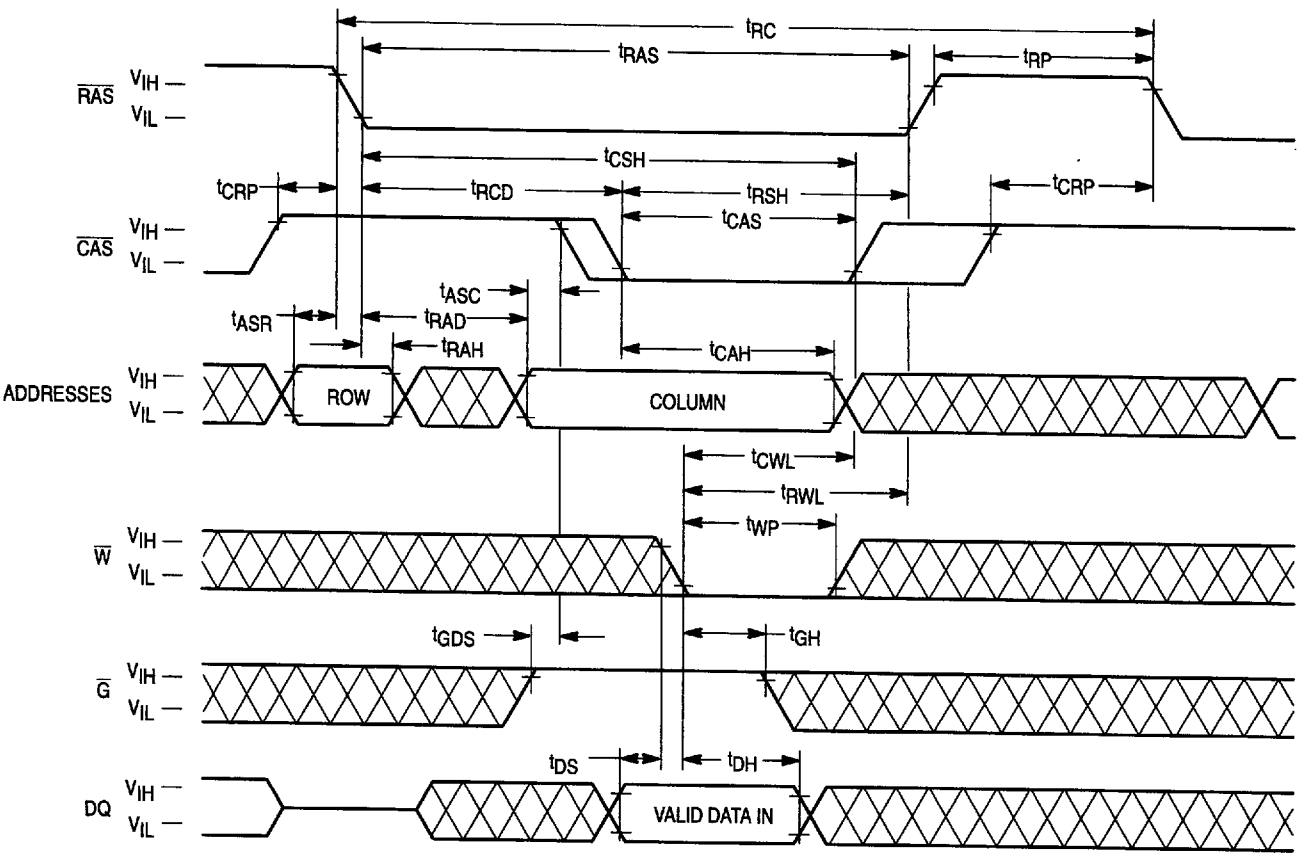
READ CYCLE



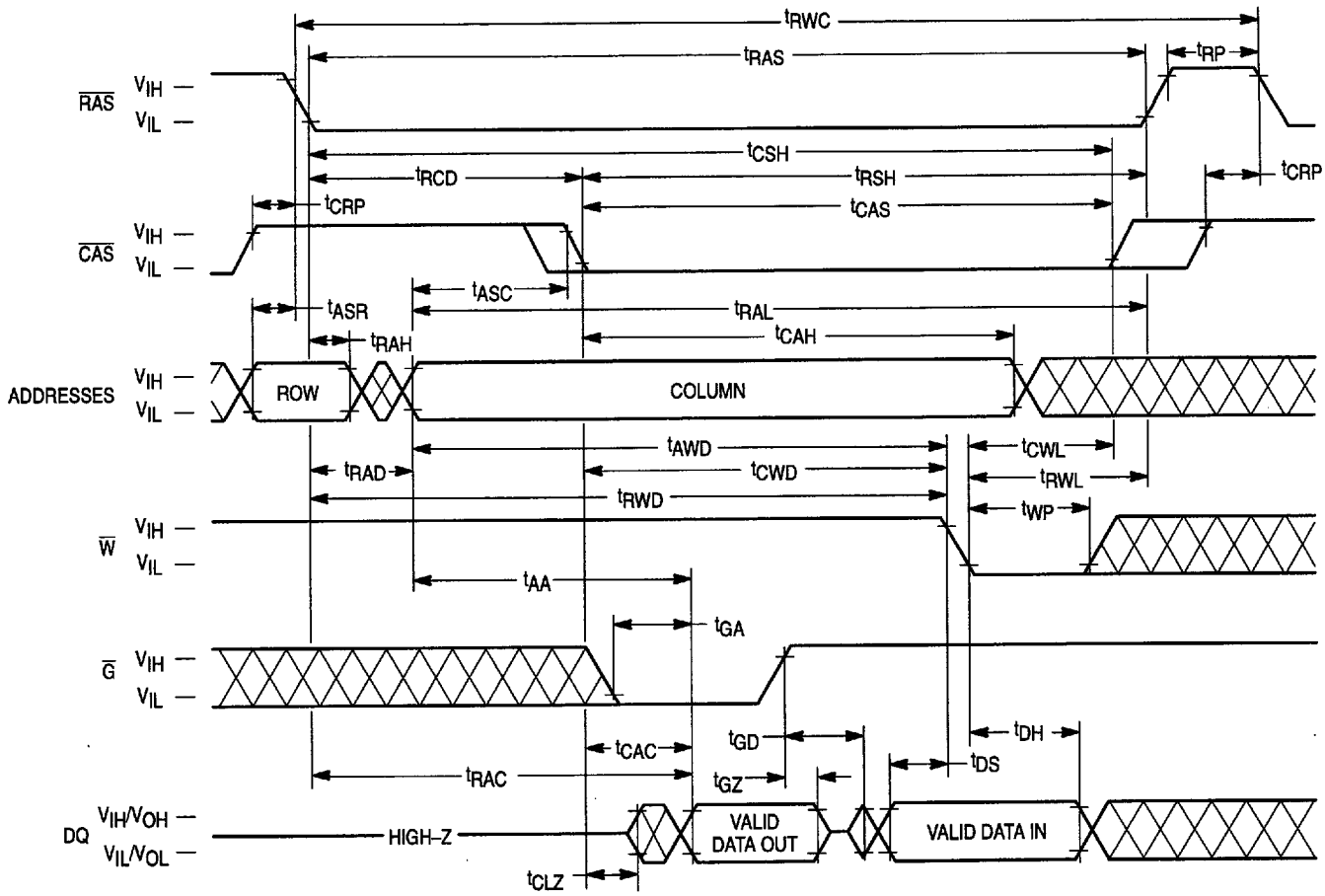
WRITE CYCLE (EARLY WRITE)



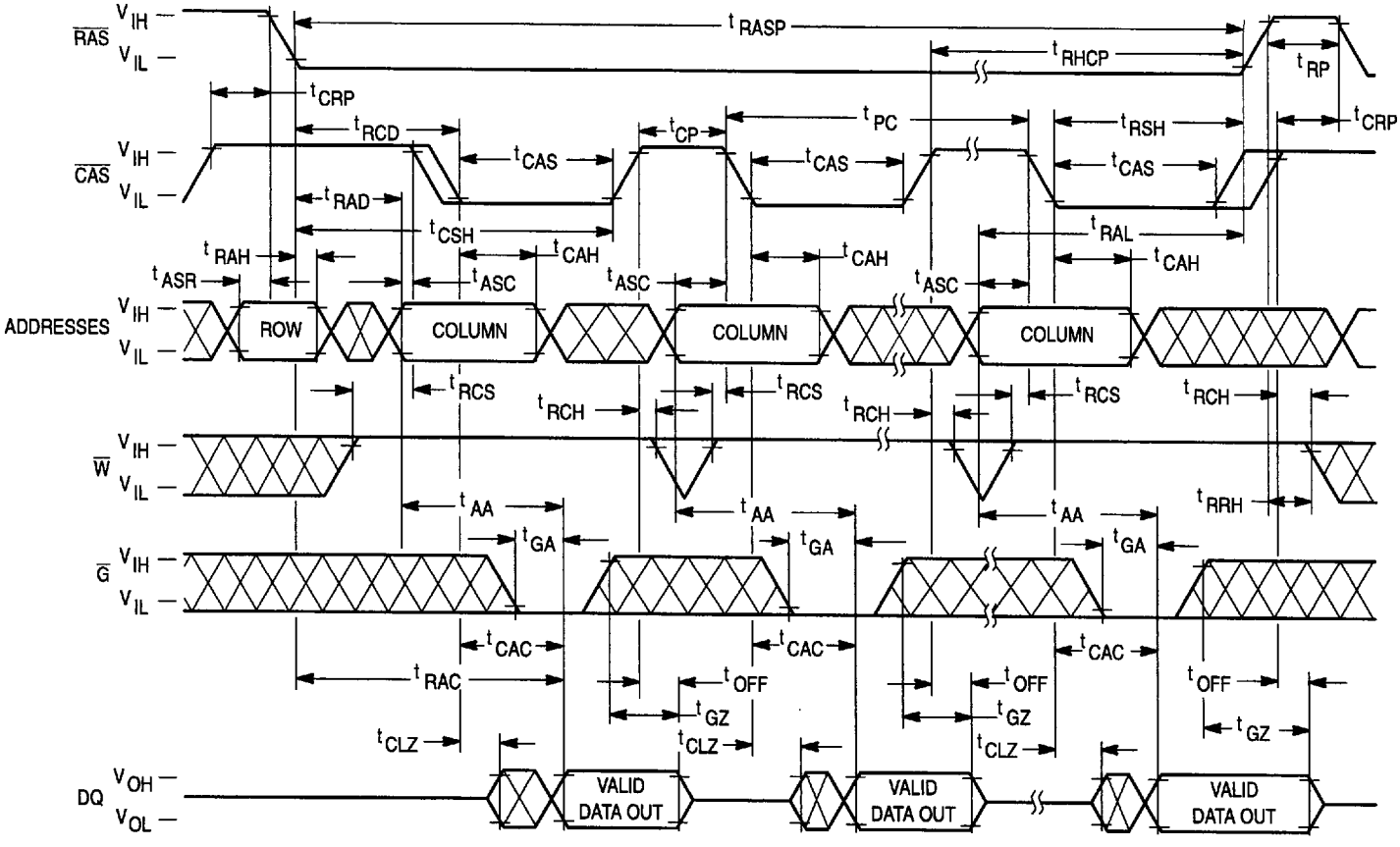
WRITE CYCLE (G CONTROLLED)



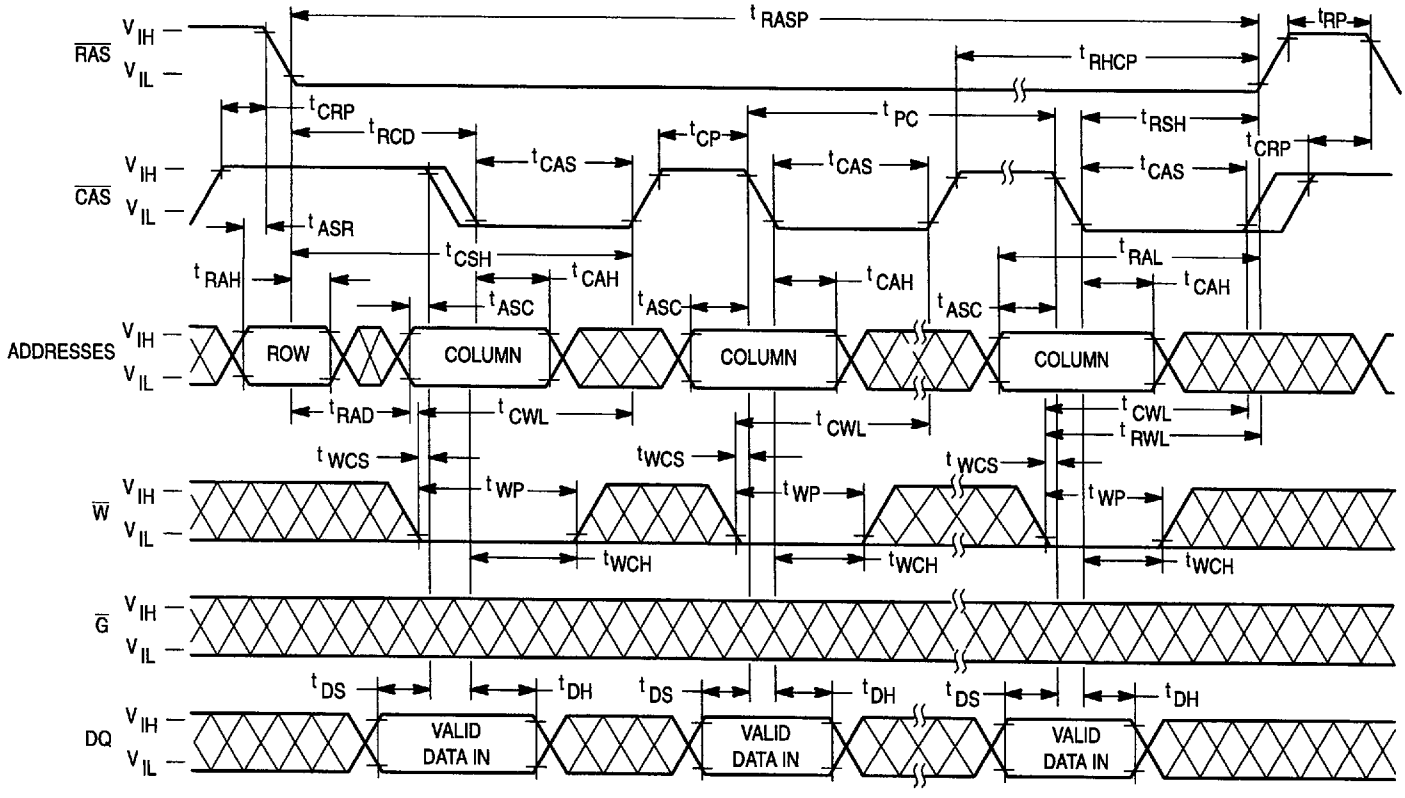
READ–WRITE CYCLE



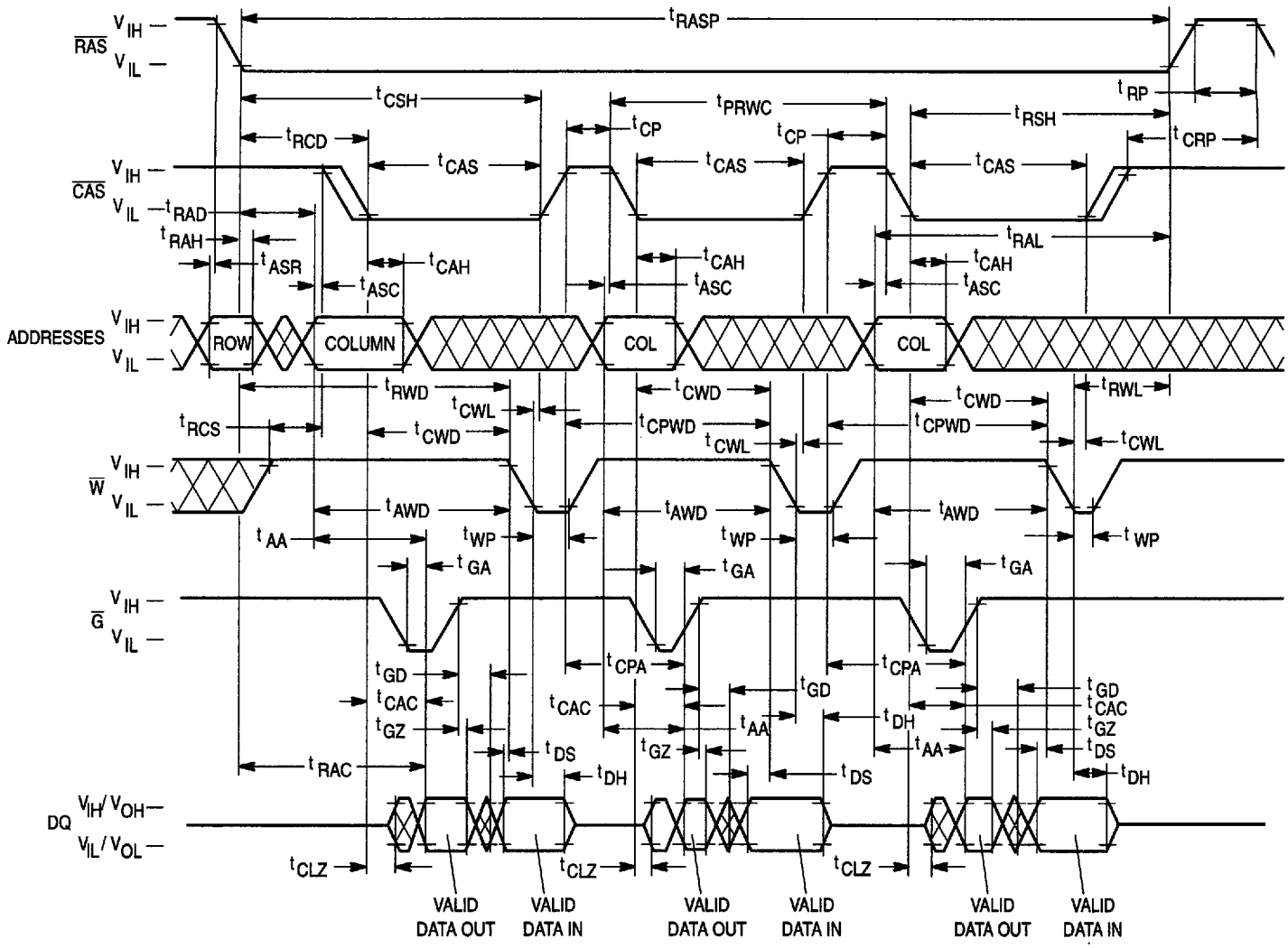
FAST PAGE MODE READ CYCLE



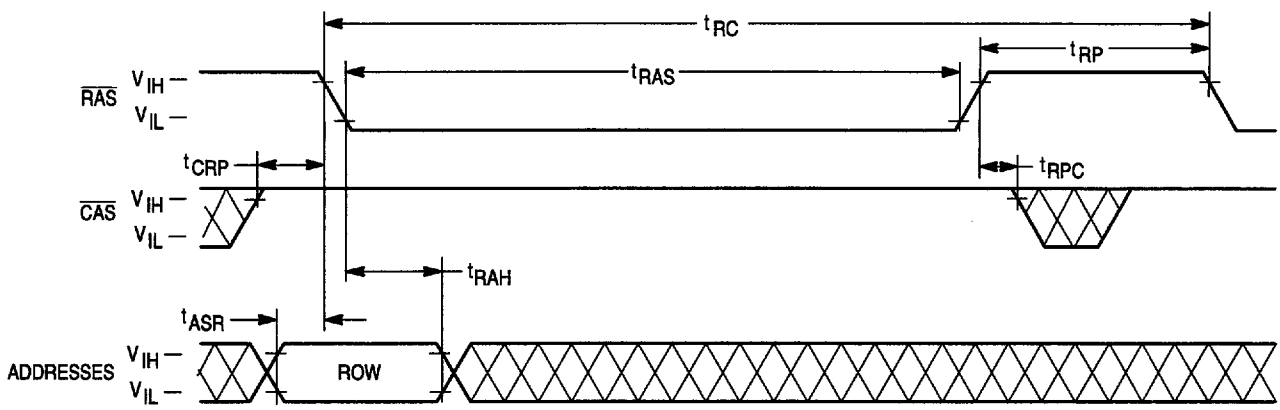
FAST PAGE MODE WRITE CYCLE (EARLY WRITE)



FAST PAGE MODE READ–WRITE CYCLE

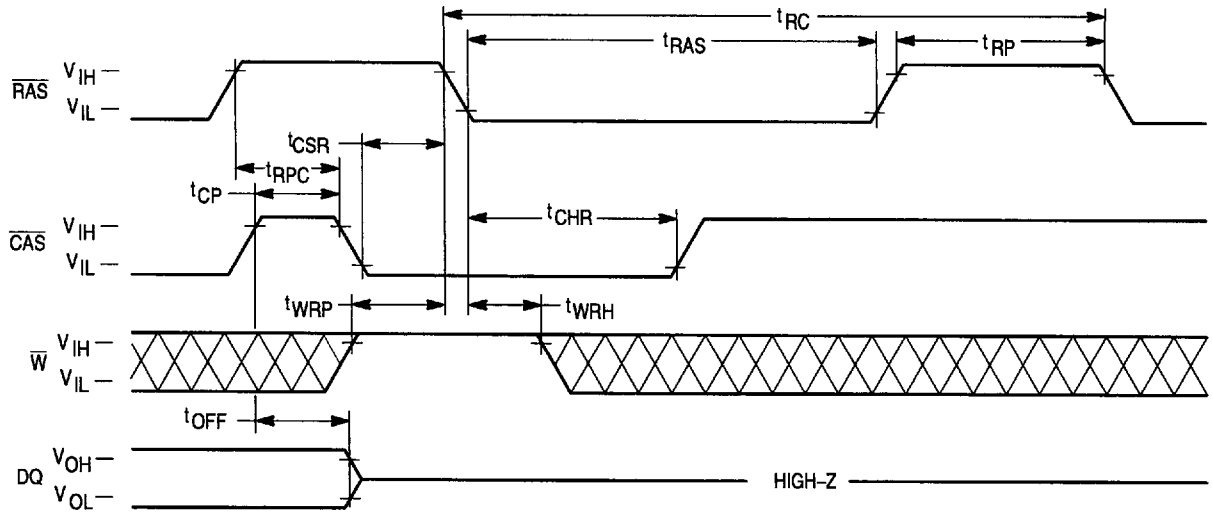


RAS–ONLY REFRESH CYCLE



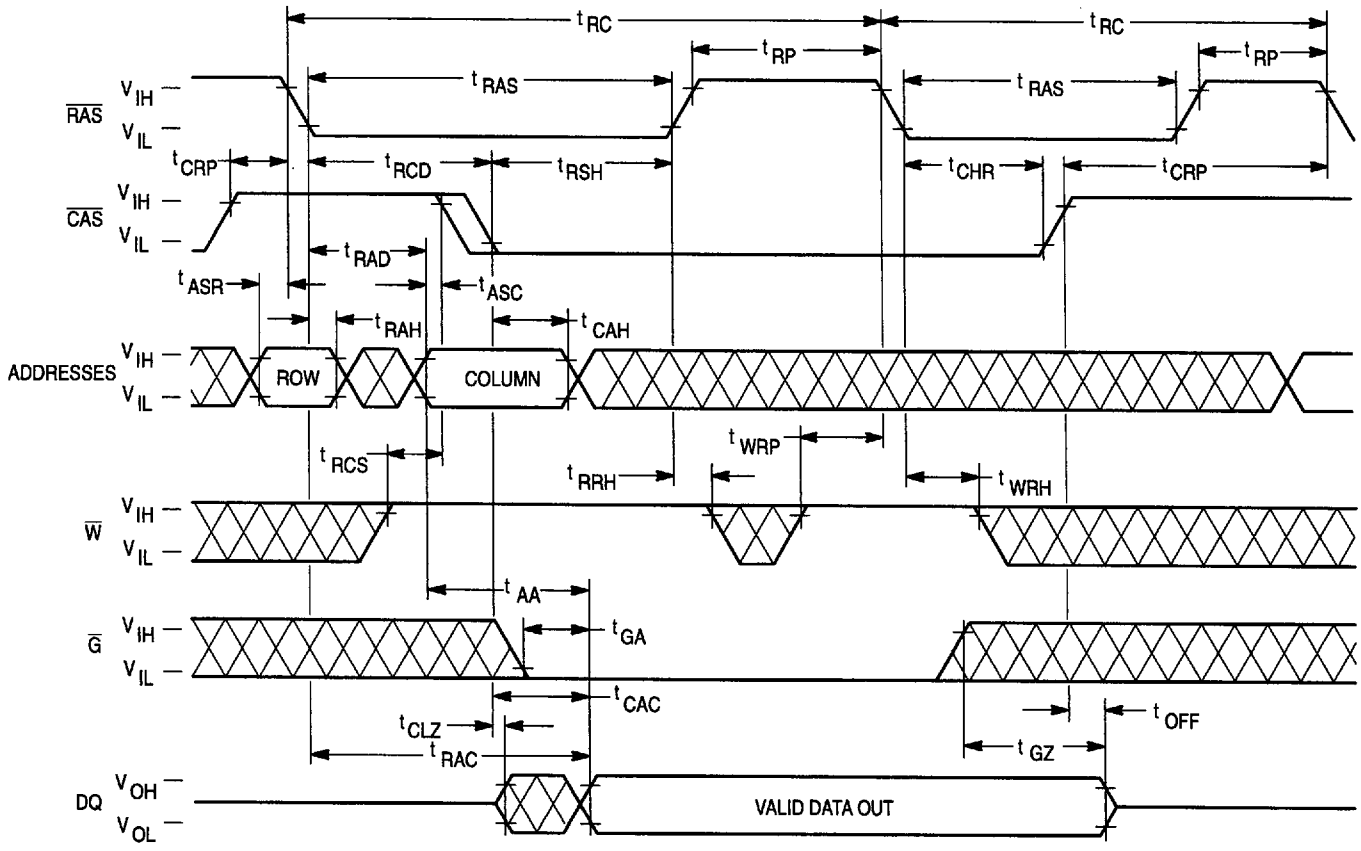
NOTE: $\overline{W}$, $\overline{G}$ = H or L.
DQ = Open.

$\overline{CAS}$ BEFORE $\overline{RAS}$ REFRESH CYCLE

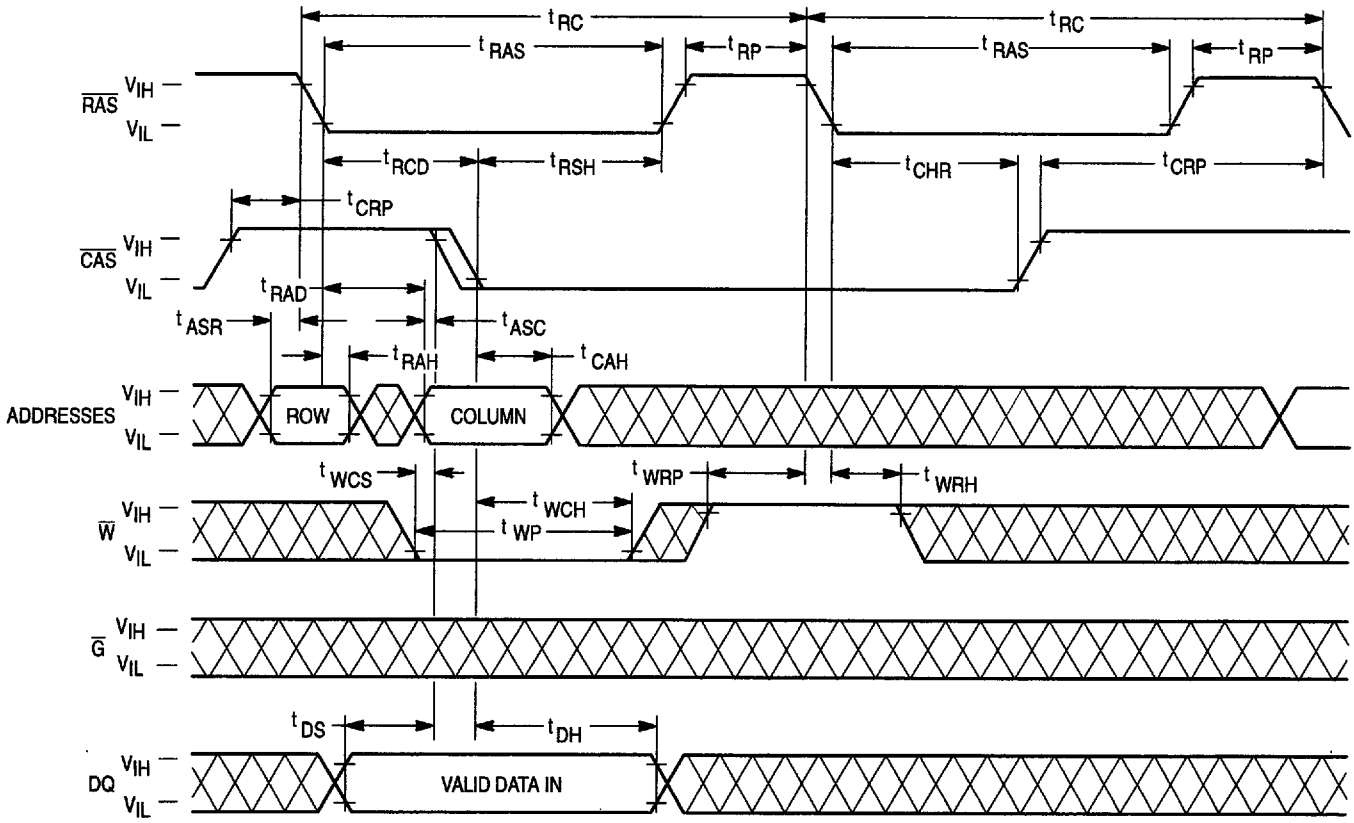


NOTE: Addresses = H or L.

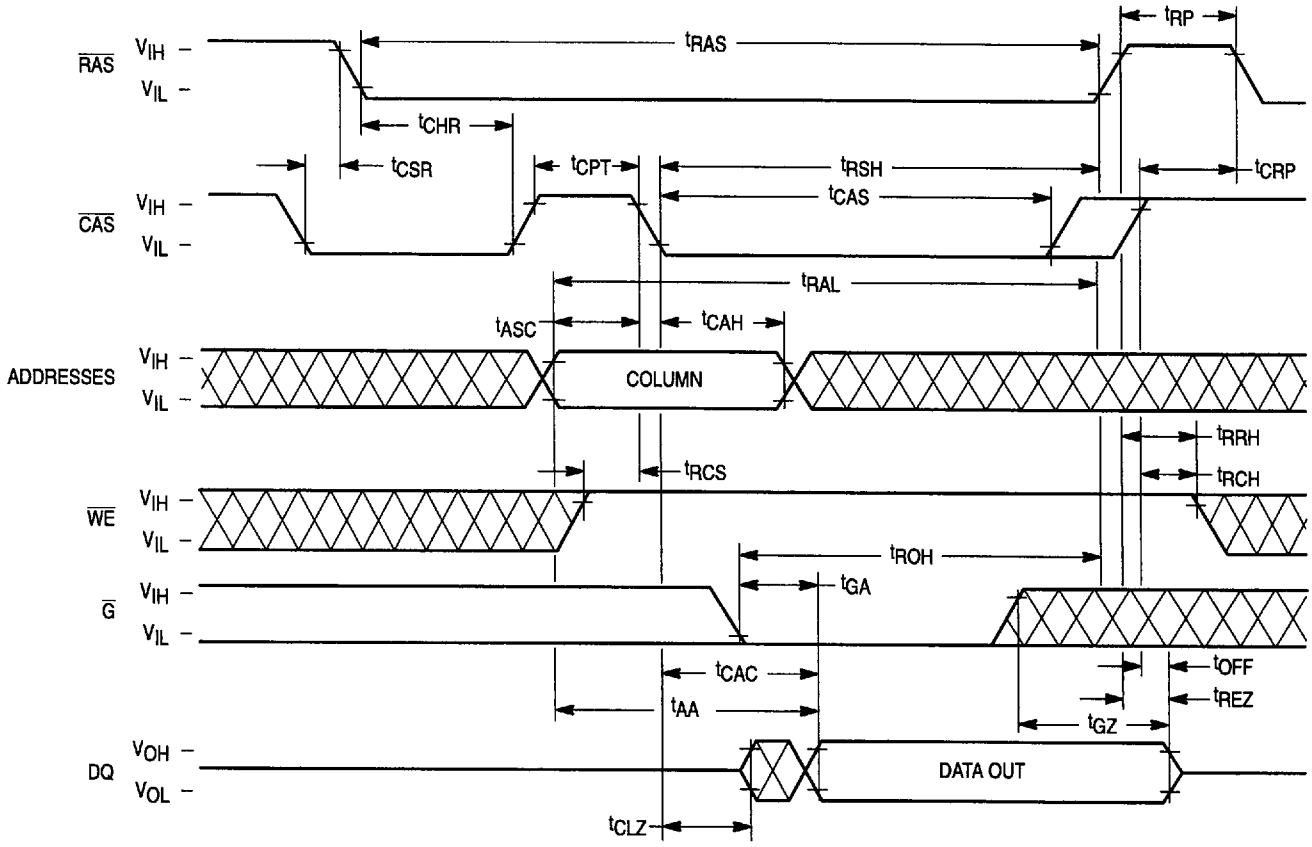
HIDDEN REFRESH CYCLE (READ)



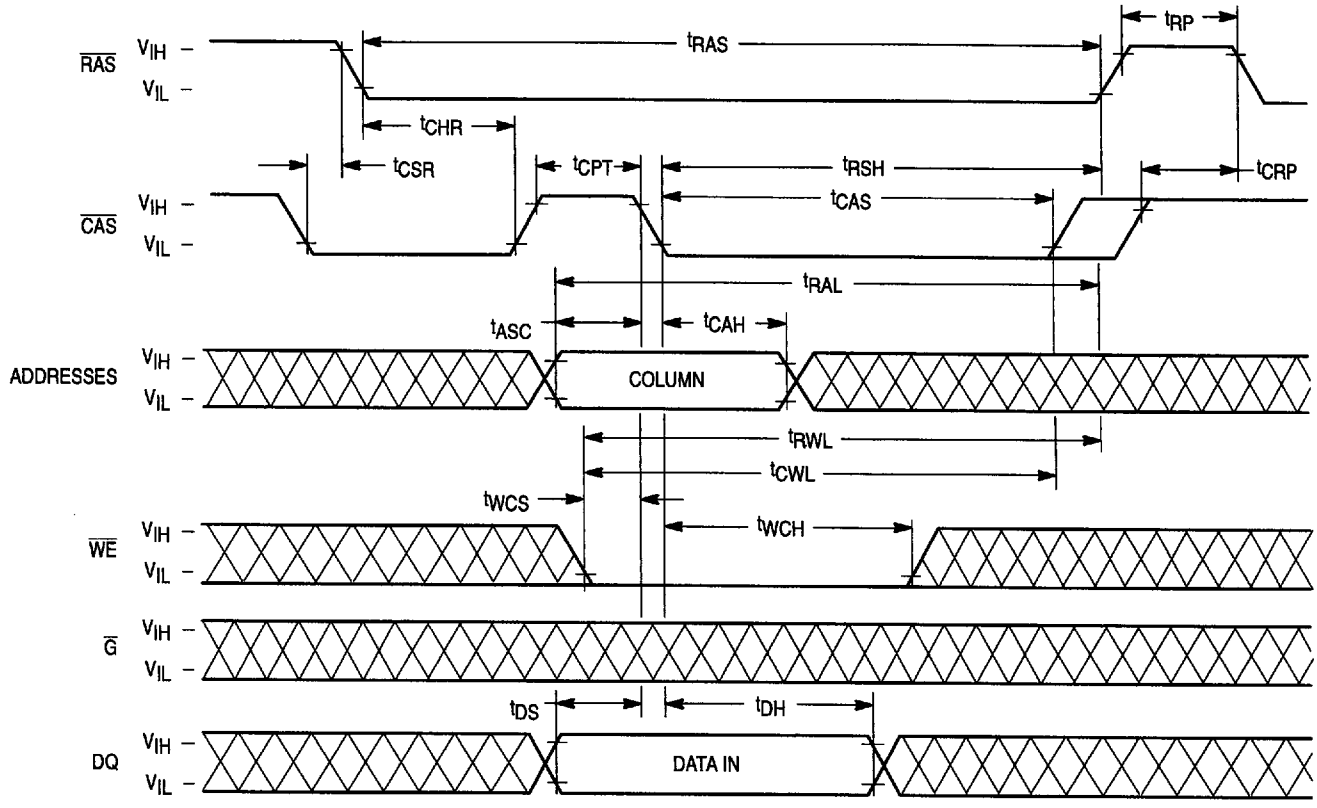
HIDDEN REFRESH CYCLE (WRITE)



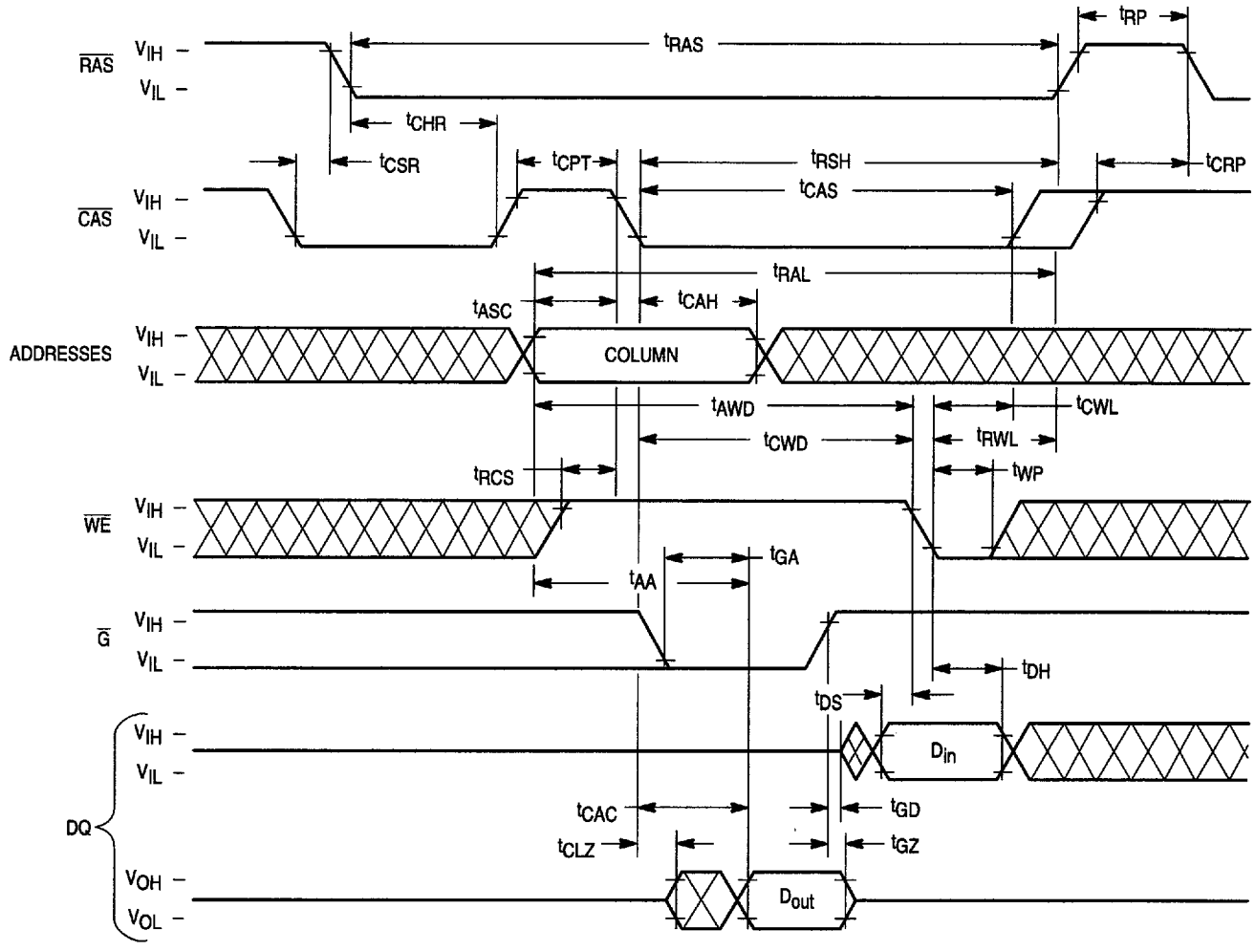
CAS BEFORE RAS REFRESH COUNTER TEST READ CYCLE



CAS BEFORE RAS REFRESH COUNTER TEST WRITE CYCLE



$\overline{CAS}$ BEFORE $\overline{RAS}$ REFRESH COUNTER TEST READ–WRITE CYCLE



DEVICE INITIALIZATION

On power–up, an initial pause of 200 µs is required for the internal substrate generator to establish the correct bias voltage. This must be followed by a minimum of eight active cycles of the row address strobe (clock) to initialize all dynamic nodes within the RAM. During an extended inactive state (greater than 32 ms), a wakeup sequence of eight active cycles is necessary to ensure proper operation.

ADDRESSING THE RAM

The eleven address pins on the device are time multiplexed at the beginning of a memory cycle by two clocks, row address strobe ($\overline{RAS}$) and column address strobe ($\overline{CAS}$), into two separate 11–bit address fields. A total of 22 address bits, 11 rows and 11 columns, will decode one of the word locations in the device. $\overline{RAS}$ active transition is followed by $\overline{CAS}$ active transition (active = V_{IL}, t_{RCD} minimum) for all read or write cycles. The delay between $\overline{RAS}$ and $\overline{CAS}$ active transitions, referred to as the **multiplex window**, gives a system designer flexibility in setting up the external addresses into the RAM.

The external $\overline{CAS}$ signal is ignored until an internal $\overline{RAS}$ signal is available. This "gate" feature on the external $\overline{CAS}$ clock enables the internal $\overline{CAS}$ line as soon as the row address hold time (t_{RAH}) specification is met (and defines t_{RCD} minimum). The multiplex window can be used to absorb skew delays in switching the address bus from row to column addresses and in generating the $\overline{CAS}$ clock.

There are three other variations in addressing the module family per device: $\overline{RAS}$–only refresh cycle, $\overline{CAS}$ before $\overline{RAS}$ refresh cycle, and page mode. All are discussed in separate sections that follow.

READ CYCLE

The DRAM may be read with four different cycles: "normal" random read cycle, fast page mode read cycle, read–write cycle, and fast page mode read–write cycle. The normal read cycle is outlined here, while the other cycles are discussed in separate sections.

The normal read cycle begins as described in **ADDRESSING THE RAM**, with $\overline{RAS}$ and $\overline{CAS}$ active transitions latching the desired bit location. The write ($\overline{W}$) input level must be high (V_{IH}), t_{RCS} (minimum) before the $\overline{CAS}$ or active transition, to enable read mode.

Both the $\overline{RAS}$ and $\overline{CAS}$ clocks trigger a sequence of events that are controlled by several delayed internal clocks. The internal clocks are linked in such a manner that the read access time of the device is independent of the address multiplex window.

Both $\overline{CAS}$ and output enable ($\overline{G}$) control read access time: $\overline{CAS}$ must be active before or at t_{RCD} maximum and $\overline{G}$ must be active t_{RAC}–t_{GA} (both minimum) after $\overline{RAS}$ active transition to guarantee valid data out (Q) at t_{RAC}. If the t_{RCD} maximum is exceeded and/or $\overline{G}$ active transition does not occur in time, read access time is determined by either the $\overline{CAS}$ or $\overline{G}$ clock active transition (t_{CAC} or t_{GA}).

WRITE CYCLE

The user can write to the DRAM with any of four cycles: early write, late write, fast page mode early write, and fast page mode read–write. Early and late write modes are discussed here, while fast page mode write operation is covered in a separate section.

A write cycle begins as described in **ADDRESSING THE RAM**. Write mode is enabled by the transition of $\overline{W}$ to active (V_{IL}). Early and late write modes are distinguished by the active transition of $\overline{W}$, with respect to $\overline{CAS}$. Minimum active time t_{RAS} and t_{CAS}, and precharge time t_{RP}, apply to write mode, as in the read mode.

An early write cycle is characterized by $\overline{W}$ active transition at minimum time t_{WCS} before $\overline{CAS}$ active transition. Column address setup and hold times (t_{ASC}, t_{CAH}) and data in (D) setup and hold times (t_{DS}, t_{DH}) are referenced to in an early write cycle. $\overline{RAS}$ and $\overline{CAS}$ clocks must stay active for t_{RWL} and t_{CWL}, respectively, after the start of the early write operation to complete the cycle.

Q remains in three–state condition throughout an early write cycle because $\overline{W}$ active transition precedes or coincides with $\overline{CAS}$ active transition, keeping data–out buffers disabled.

A late–write cycle (referred to as $\overline{G}$–controlled write) occurs when $\overline{W}$ active transition is made after $\overline{CAS}$ active transition. $\overline{W}$ active transition could be delayed for almost 10 microseconds after $\overline{CAS}$ active transition, ($t_{RCD} + t_{CWD} + t_{RWL} + 2t_T$) ≤ t_{RAS}, if other timing minimums (t_{RCD}, t_{RWL}, and t_T) are maintained. D timing parameters are referenced to $\overline{W}$ active transition in a late write cycle. Output buffers are enabled by $\overline{CAS}$ active transition. Outputs are switched off by $\overline{G}$ inactive transition, which is required to write to the device. Q may be indeterminate (see note 15 of AC Operating Conditions table). $\overline{RAS}$ and $\overline{CAS}$ must remain active for t_{RWL} and t_{CWL}, respectively, after $\overline{W}$ active transition to complete the write cycle. $\overline{G}$ must remain inactive for t_{GH} after $\overline{W}$ active transition to complete the write cycle.

READ–WRITE CYCLE

A read–write cycle performs a read and then a write at the same address, during the same cycle. This cycle is basically a late write cycle, as discussed in the **WRITE CYCLE** section, except $\overline{W}$ must remain high for t_{CWD} and/or t_{AWD} minimum, to guarantee valid Q before writing the bit.

PAGE MODE CYCLES

Page mode allows fast successive data operations at all column locations on a selected row. Read access time in page mode (t_{CAC}) is typically half the regular $\overline{RAS}$ clock access time, t_{RAC}. Page mode operation consists of keeping $\overline{RAS}$ active while toggling $\overline{CAS}$ between V_{IH} and V_{IL}. The row is latched by $\overline{RAS}$ active transition, while each $\overline{CAS}$ active transition allows selection of a new column location on the row.

A page mode cycle is initiated by a normal read, write, or read–write cycle, as described in prior sections. Once the timing requirements for the first cycle are met, $\overline{CAS}$ transitions to inactive for minimum t_{CP}, while $\overline{RAS}$ remains low (V_{IL}). The second $\overline{CAS}$ active transition while $\overline{RAS}$ is low initiates the first page mode cycle (t_{PC} or t_{PRWC}). Either a read, write, or read–write operation can be performed in a page mode cycle, subject to the same conditions as in normal operation (previously described). These operations can be intermixed in consecutive page mode cycles and performed in any order. The maximum number of consecutive page mode cycles is limited by t_{RASP}. Page mode operation is ended when $\overline{RAS}$ transitions to inactive, coincident with or following $\overline{CAS}$ inactive transition.

REFRESH CYCLES

The dynamic RAM design is based on capacitor charge storage for each bit in the array. This charge will tend to

degrade with time and temperature. Each bit must be periodically **refreshed** (recharged) to maintain the correct bit state. Bits in the module require refresh every t_{RFSH}.

This is accomplished by cycling through the row addresses in sequence within the specified refresh time. All the bits on a row are refreshed simultaneously when the row is addressed. Distributed refresh implies a row refresh every 15.6 µs for the module family. Burst refresh, a refresh of all rows consecutively, must be performed every t_{RFSH}.

A normal read, write, or read–write operation to the RAM will refresh all the bits associated with the particular row decoded. Three other methods of refresh, **$\overline{RAS}$–only refresh, $\overline{CAS}$ before $\overline{RAS}$ refresh,** and **hidden refresh** are available on this device for greater system flexibility.

$\overline{RAS}$–Only Refresh

$\overline{RAS}$–only refresh consists of $\overline{RAS}$ transition to active, latching the row address to be refreshed, while $\overline{CAS}$ remains high (V_{IH}) throughout the cycle. An external counter should be employed to ensure that all rows are refreshed within the specified limit.

$\overline{CAS}$ Before $\overline{RAS}$ Refresh

$\overline{CAS}$ before $\overline{RAS}$ refresh is enabled by bringing $\overline{CAS}$ active before $\overline{RAS}$. This clock order activates an internal refresh counter that generates the row address to be refreshed. External address lines are ignored during the automatic refresh cycle. The output buffer remains at the same state it was in during the previous cycle (hidden refresh).

Hidden Refresh

Hidden refresh allows refresh cycles to occur while maintaining valid data at the output pin. Holding $\overline{CAS}$ active at the end of a read or write cycle while $\overline{RAS}$ cycles inactive for t_{RP} and back to active starts the hidden refresh. This is essentially the execution of a $\overline{CAS}$ before $\overline{RAS}$ refresh from a cycle in progress (see Figure 1).

$\overline{CAS}$ BEFORE $\overline{RAS}$ REFRESH COUNTER TEST

The internal refresh counter of this device can be tested with a **$\overline{CAS}$ before $\overline{RAS}$ refresh counter test**. This test is performed with a read–write operation. During the test, the internal refresh counter generates the row address, while the external address supplies the column address. The entire array is refreshed after completing one cycle for every column, as indicated by the check data written in each row. See **$\overline{CAS}$ before $\overline{RAS}$ refresh counter test cycle** timing diagram.

The test can be performed after a minimum of eight **$\overline{CAS}$ before $\overline{RAS}$** initialization cycles. Test procedure:

1. Write 0s into all memory cells with normal write mode.
2. Select a column address, read 0 out and write 1 into the cell by performing the **$\overline{CAS}$ before $\overline{RAS}$ refresh counter test, read–write cycle**. Repeat this operation for every column.
3. Read the 1s that were written in step two in normal read mode.
4. Using the same starting column address as in step two, read 1 out and write 0 into the cell by performing the **$\overline{CAS}$ before $\overline{RAS}$ refresh counter test, read–write cycle.** Repeat this operation for every column.
5. Read 0s which were written in step four in normal read mode.
6. Repeat steps one through five using complement data.

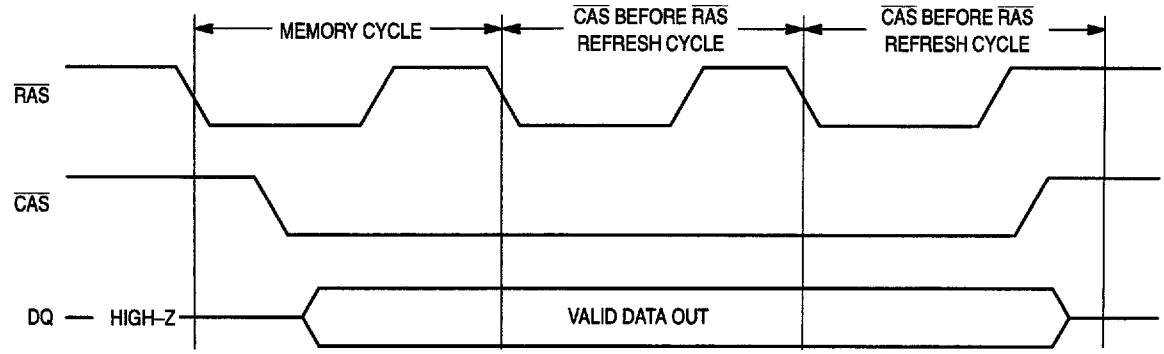
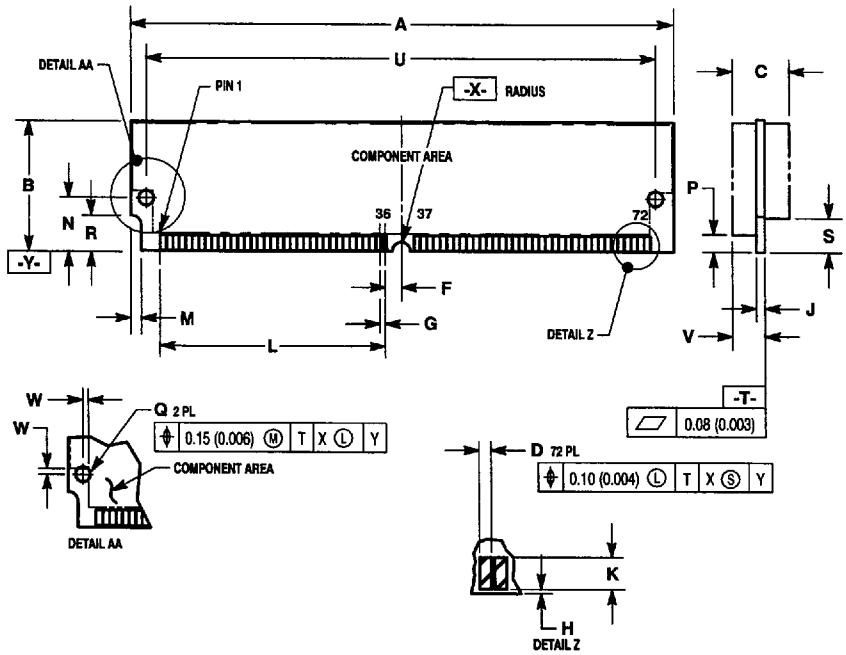


Figure 1. Hidden Refresh Cycle

PACKAGE DIMENSIONS

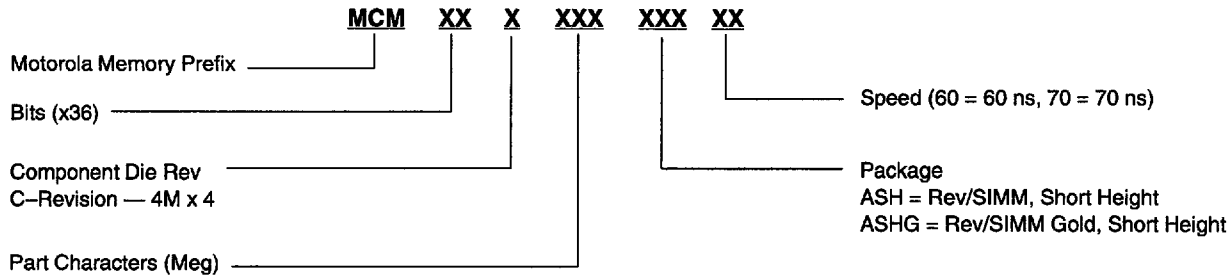
72–LEAD SIMM
CASE 866–02



NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH.
3. CARD THICKNESS APPLIES ACROSS TABS AND INCLUDES PLATING AND/OR METALIZATION.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
A	107.82	108.08	4.245	4.255
B	25.27	25.53	0.995	1.005
C	—	9.14	—	0.360
D	1.02	1.07	0.040	0.042
F	3.18 BSC		0.125 BSC	
G	1.27 BSC		0.050 BSC	
H	—	0.25	—	0.010
J	1.19	1.37	0.047	0.054
K	0.25	—	0.100	—
L	44.45 REF		1.750 REF	
M	1.90	2.16	0.075	0.085
N	10.16 BSC		0.400 BSC	
P	3.18	—	0.125	—
Q	3.12	3.22	0.123	0.127
R	6.22	6.48	0.245	0.255
S	5.72	—	0.225	—
U	101.19 BSC		3.984 BSC	
V	—	5.28	—	0.208
W	1.12	—	0.044	—
X	1.52	1.63	0.060	0.064

ORDERING INFORMATION
(Order by Full Part Number)



Full Part Numbers — MCM36C404ASH60
MCM36C404ASHG60

MCM36C404ASH70
MCM36C404ASHG70

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MCM36C804ASHG60

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